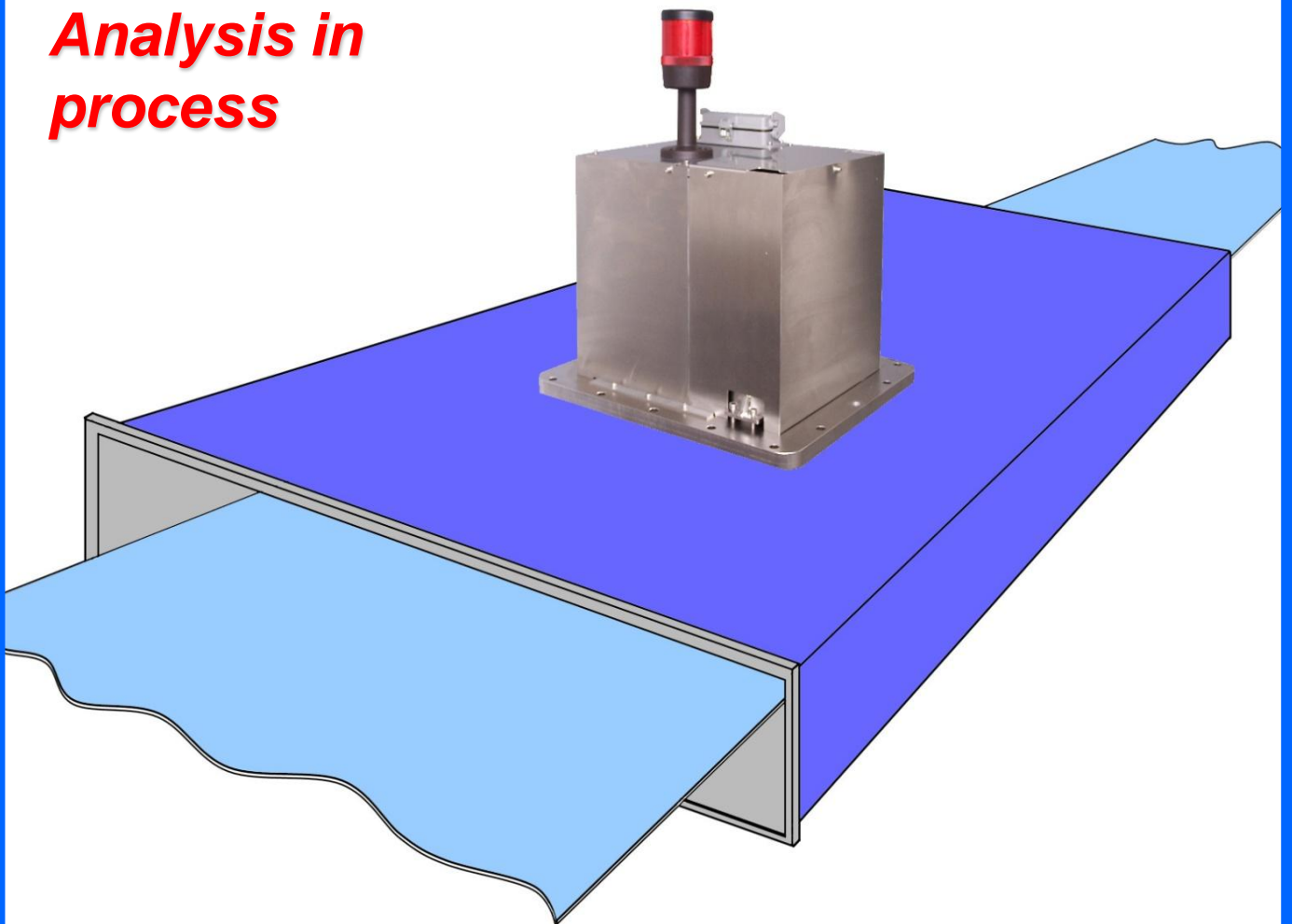
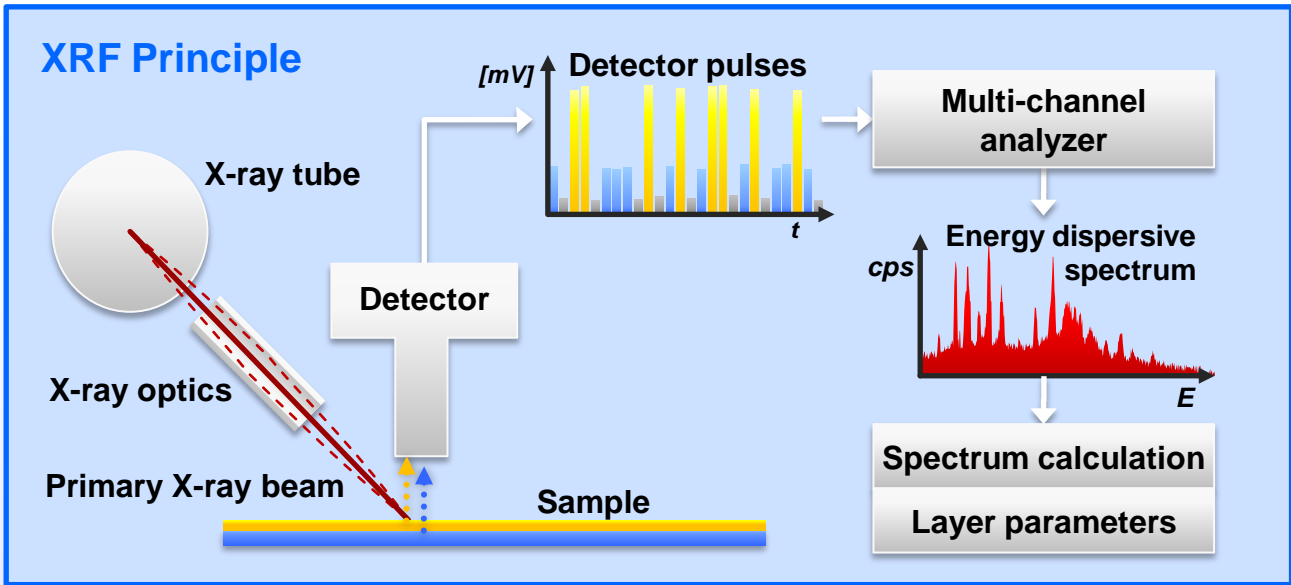


Online **XRF-Analysis** of Metal Coatings in Process

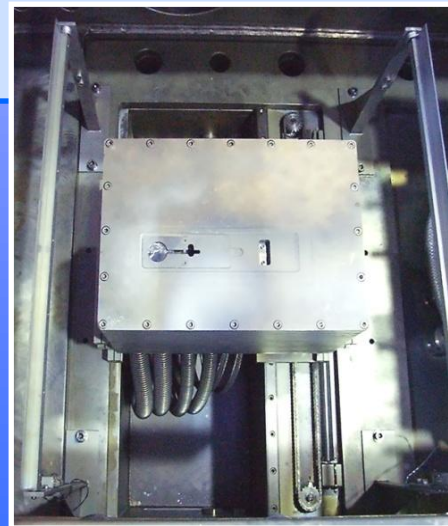
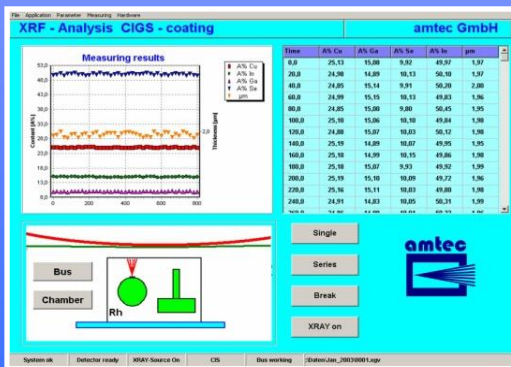
- **Measuring of multi-layers, alloy-layers**
- **Thickness: nm ... μm / element content: ppm ... %**
- **Data interface via field bus to process control unit**
- **Shielding against heat, particles, electrical fields**
- **Operational uptime: > 98 %**
- **Measuring method corresponding ISO 3497 / DIN 50987**

***Analysis in
process***





- ✓ Analysis of multi-layers and alloy-layers, nanometer light metal coatings too
- ✓ Field of application: solar cells, fuel cells, magnetic layers, barrier layers, ...
- ✓ Measuring period: 5 s ...
- ✓ Reproducibility: 3 %
- ✓ Substrate temperature up to 500 °C
- ✓ Fieldbus interface to process control system
- ✓ Easy-to-use ergonomic human-machine interface
- ✓ Visualization of measurement data with various parameters
- ✓ High operational reliability by internal status control
- ✓ Measuring and positioning in vacuum possible
- ✓ X-ray source with optimized quantum efficiency
- ✓ Maintenance-free Peltier-cooled detector
- ✓ X-ray optics
- ✓ Fully radiation protected in conformity with German regulation for using X-ray



Interested? → Feel free to contact us!

amtec Analysenmesstechnik GmbH

Braunstrasse 23-25
D-04347 Leipzig

Phone +49-(0)341-230 27 60
Fax +49-(0)341-230 27 70

The manufacturer reserves the right to make changes without notice.

info@amtec-spectro.de
www.amtec-spectro.de